

Fig.1 X-ray diffraction pole figure image of ZnTe111. The origin of the pole figure is the S-nanofacet plane surface of the r- and S-nano facet substrate (a) without offset angle, and (b) with an offset angle of  $17.66^\circ$

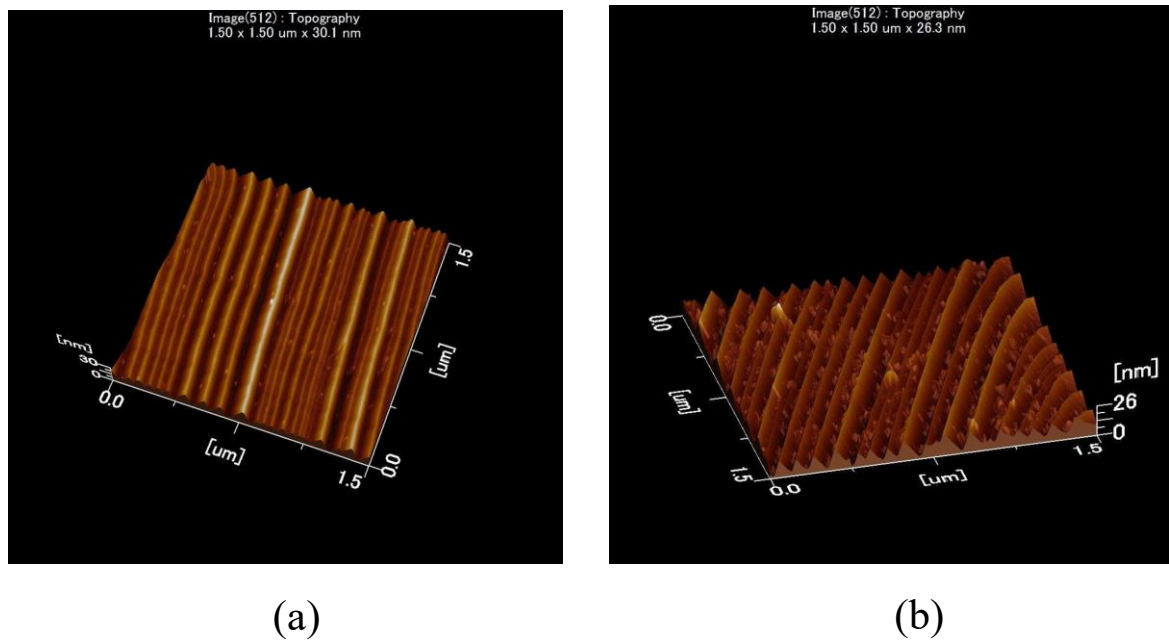


Fig.2 AFM image of the sample surface of the r- and S-plane sapphire nanofaceted substrate after nucleation. Annealing was performed at (a)  $1400^\circ\text{C}$  for 20h, and (b)  $1400^\circ\text{C}$  for 40h. Improved uniformity of the substrate surface was confirmed for sample with a longer annealing duration.